Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/630,691	ONOMATSU ET AL.	
Examiner	Art Unit	
Sherrie Hsia	2622	

	 			
SEARCHED				
Class	Subclass	Date	Examiner	
348	714, 716, 718-721, 552-554	4/06	SI	
	705, 706			
	725, 731			
H04N	5/44			
	9/64			
	_			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interfor	Junton	4/06	SV
1300	<i>y</i>	/	

SEARCH N		′)
	DATE	EXMR
EAST Consulted with V. Kostak	4/06	SM